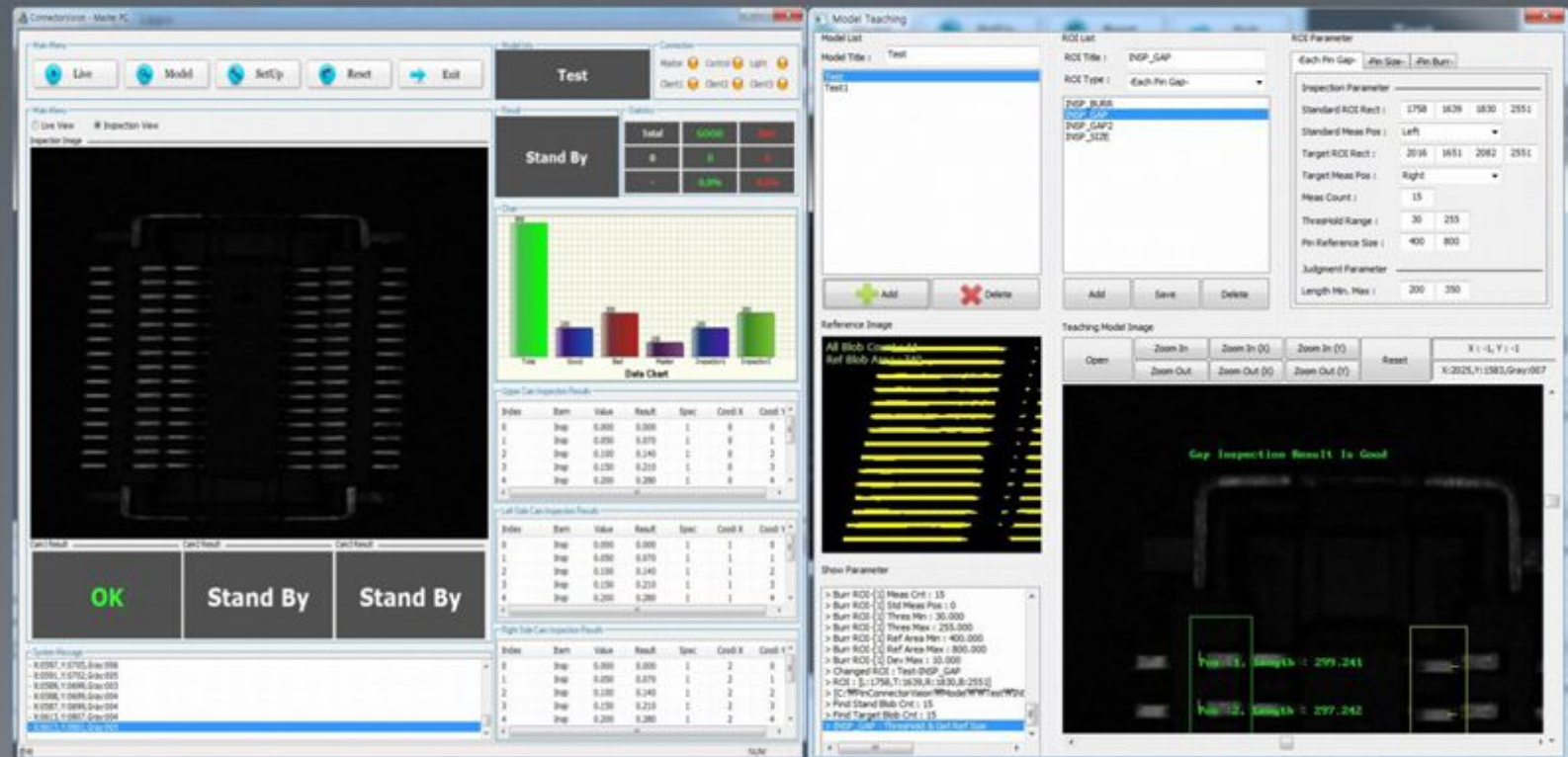


Pin Connector Visual Inspection System

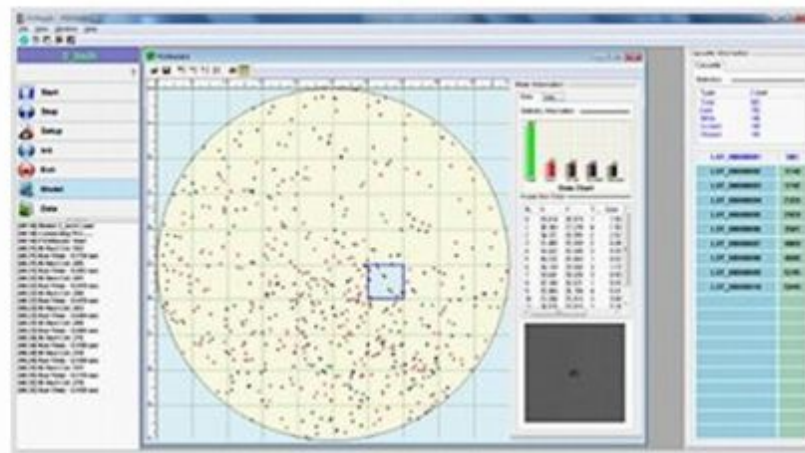


Inspection Item & Component

- 개발 시기 : 2013, 단독 개발
- 검사 항목 : Pin Burr, Pin Size, Pin Gap Length 치수 측정
- 검사기 형태 : In-line, Line Scan Camera

LED

PSS Wafer Visual Inspection System



Main User Interface



Line Scan Camera
Optical Module



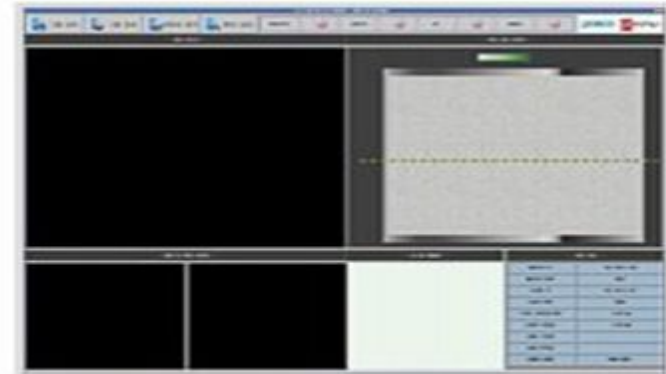
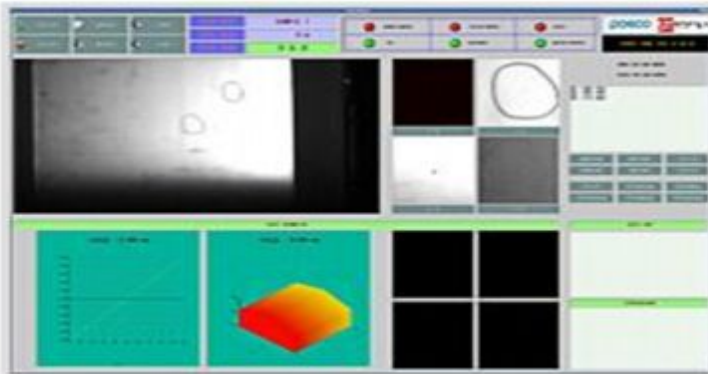
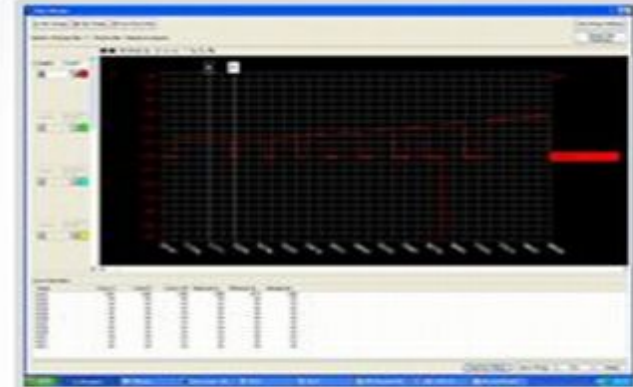
Transfer Robot

Inspection Item & Component

- ☞ 개발 시기 : 2012, 검사 모듈 개발
- ☞ 검사 항목 : Stain, Foreign Substance, Scratch, Stepper Line 외관 검사
- ☞ 검사기 형태 : In-line, Line Scan Camera

Steel Surface Visual Inspection System

1. GUI



2. Inspection Item & Component

- ☞ 개발 시기 : 2009, 검사 모듈 개발
- ☞ 검사 항목 : Surface Scratch, Foreign Substance 외관 검사, Defect Object 높이 측정
- ☞ 검사기 형태 : In-line, Line Scan Camera, 3D Laser Profile

ELECTRONICS Multi-Layer Ceramic Capacitor Align Inspection System

1. GUI

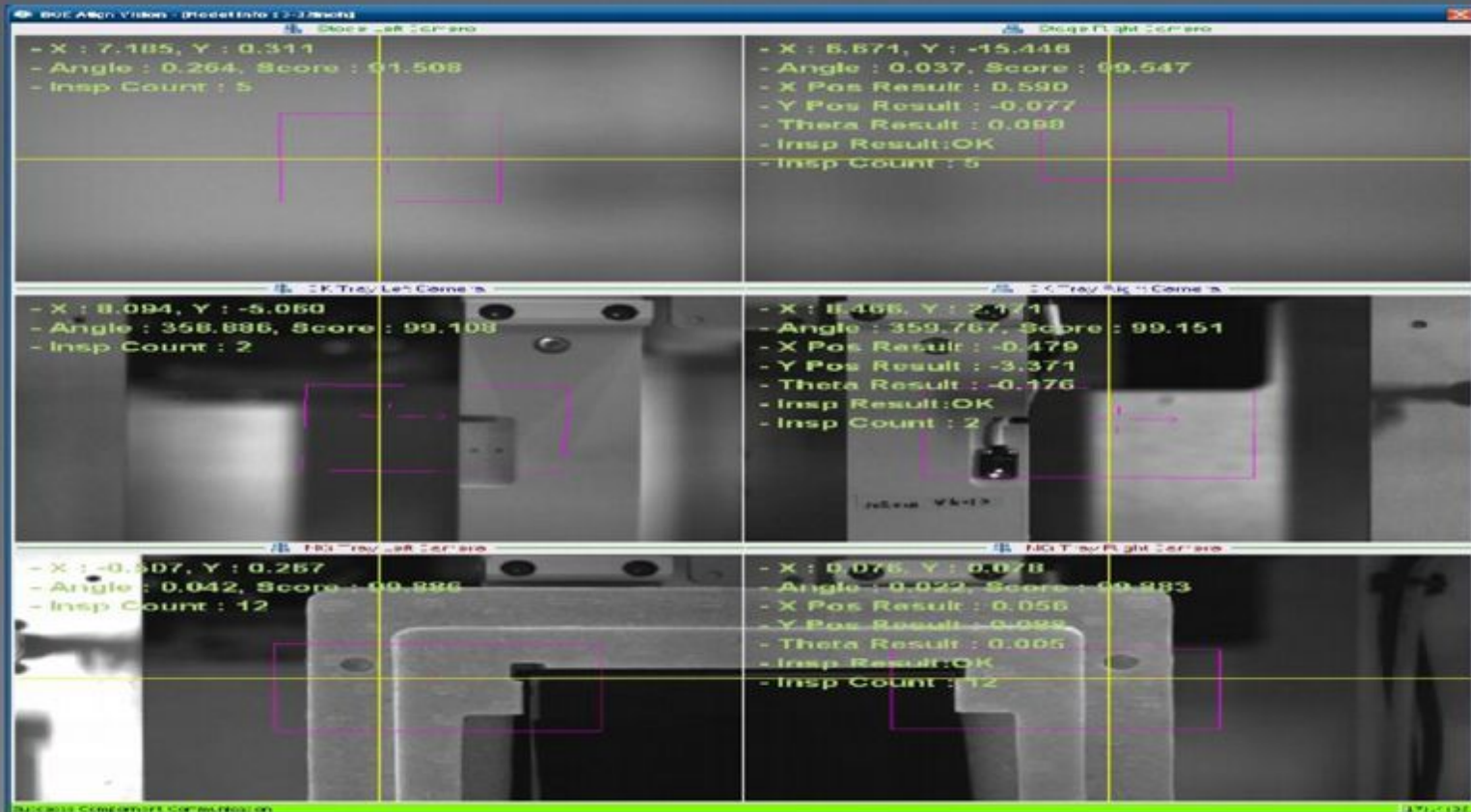


2. Inspection Item & Component

- ☞ 개발 시기 : 2013, 검사 모듈 개발 (Library 형태 제공)
- ☞ 검사 항목 : Chip Align, X-Y-Theta, Size 치수 측정
- ☞ 검사기 형태 : Off-line, Area Scan Camera

Glass Align Visual Inspection System

1. GUI



2. Inspection Item & Component

- ☞ 개발 시기 : 2013, 단독 개발
- ☞ 검사 항목 : X-Y-Theta Align 측정
- ☞ 검사기 형태 : Off-Line, Area Scan Camera

CCTV

Thermal Camera CCTV

1. GUI



2. Inspection Item & Component

- 개발 시기 : 2014, 단독 개발
- 검사 항목 : Motion Detecting, Fence Monitoring
- 검시기 형태 : In-line, Thermal Area Scan Camera